

Notice of References Cited	Application/Control No. 10/668,706		Applicant(s)/Patent Under Reexamination KALHAN, AMIT	
	Examiner Emmanuel Bayard		Art Unit 2611	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,405,047	06-2002	Moon, Yong-Woon	455/456.1
*	B	US-6,898,197	05-2005	Lavean, Gil	370/335
*	C	US-7,113,538	09-2006	Chen et al.	375/150
*	D	US-2006/0040616	02-2006	Wheatley, CharlesE	455/067.11
*	E	US-6,016,322	01-2000	Goldman, Herbert B.	370/508
*	F	US-6,351,644	02-2002	Hussain et al.	455/456.5
*	G	US-6,075,990	06-2000	Shin, Yeong-Jong	455/440
*	H	US-6,577,616	06-2003	Chaudry et al.	370/342
*	I	US-5,670,964	09-1997	Dent, Paul W.	342/457
*	J	US-2005/0220051	10-2005	Lavean, Gil	370/330
*	K	US-6,085,091	07-2000	Yoo et al.	455/441.
*	L	US-2003/0054813	03-2003	Riley et al.	455/424
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

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